Unit: mm

.4±0.2

0.16+0.10

# 2SC5863

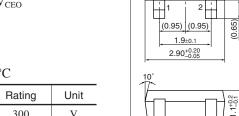
# Silicon NPN epitaxial planar type

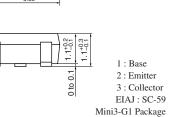
For general amplification

# Features

- $\bullet$  High collector-emitter voltage (Base open)  $V_{\mbox{CEO}}$
- $\bullet$  High transition frequency  $f_{\rm T}$

Absolute Maximum Ratings $T_a = 25^{\circ}C$						
Parameter	Symbol	Rating	Unit			
Collector-base voltage (Emitter open)	V <sub>CBO</sub>	300	V			
Collector-emitter voltage (Base open)	V <sub>CEO</sub>	300	V			
Emitter-base voltage (Collector open)	V <sub>EBO</sub>	7	V			
Collector current	I <sub>C</sub>	70	mA			
Peak collector current	I <sub>CP</sub>	100	mA			
Collector power dissipation	P <sub>C</sub>	200	mW			
Junction temperature	Tj	150	°C			
Storage temperature	T <sub>stg</sub>	-55 to +150	°C			





#### Marking Symbol: 7H

0.40+0.10

1.50<sup>+0.25</sup> 2.8<sup>+0.2</sup>

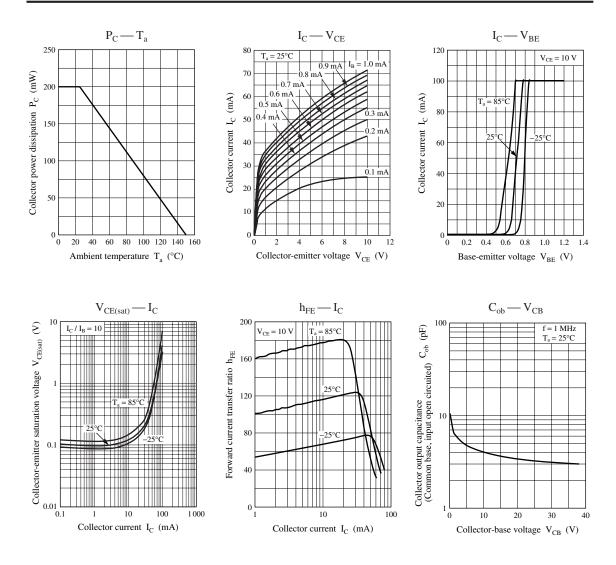
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## Electrical Characteristics $T_a = 25^{\circ}C \pm 3^{\circ}C$

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-emitter voltage (Base open)	V <sub>CEO</sub>	$I_{C} = 100 \ \mu A, I_{B} = 0$	300			V
Emitter-base voltage (Collector open)	V <sub>EBO</sub>	$I_E = 1 \ \mu A, \ I_C = 0$	7			V
Collector-emitter cutoff current (Base open)	I <sub>CEO</sub>	$V_{CE} = 120 \text{ V}, I_B = 0$			1	μΑ
Forward current transfer ratio *	h <sub>FE</sub>	$V_{CE} = 10 \text{ V}, I_C = 5 \text{ mA}$	60		220	
Collector-emitter saturation voltage	V <sub>CE(sat)</sub>	$I_{\rm C} = 50 \text{ mA}, I_{\rm B} = 5 \text{ mA}$			1.2	V
Collector output capacitance (Common base, input open circuited)	C <sub>ob</sub>	$V_{CB} = 10 \text{ V}, I_E = 0, f = 1 \text{ MHz}$			10	pF
Transition frequency	f <sub>T</sub>	$V_{CB} = 10 \text{ V}, I_E = -10 \text{ mA}, f = 200 \text{ MHz}$	50	80		MHz

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors. 2. \*: Rank classification

Rank	Q	R
h <sub>FE</sub>	60 to 150	100 to 220



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